Applicant(s)/Patent Under Application/Control No. Reexamination 10/766,587 WAKE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2822 Thanh Y. Tran **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 03-2004 Wake et al. 438/149 US-6,713,325 Α * 05-2002 365/149 US-2002/0051378 Ohsawa, Takashi В US-С US-D US-Е US-F US-G US-Н US-1 US-J US-K US-L US-М FOREIGN PATENT DOCUMENTS Date Document Number Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Х